

Forging a Future in Memory:

New Technologies, New Markets, New Applications

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V.P. Chief Memory Systems Architect

Non-Volatile Memory Seminar
Hot Chips Conference
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Memorial Auditorium
Stanford University



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July 27, 2010

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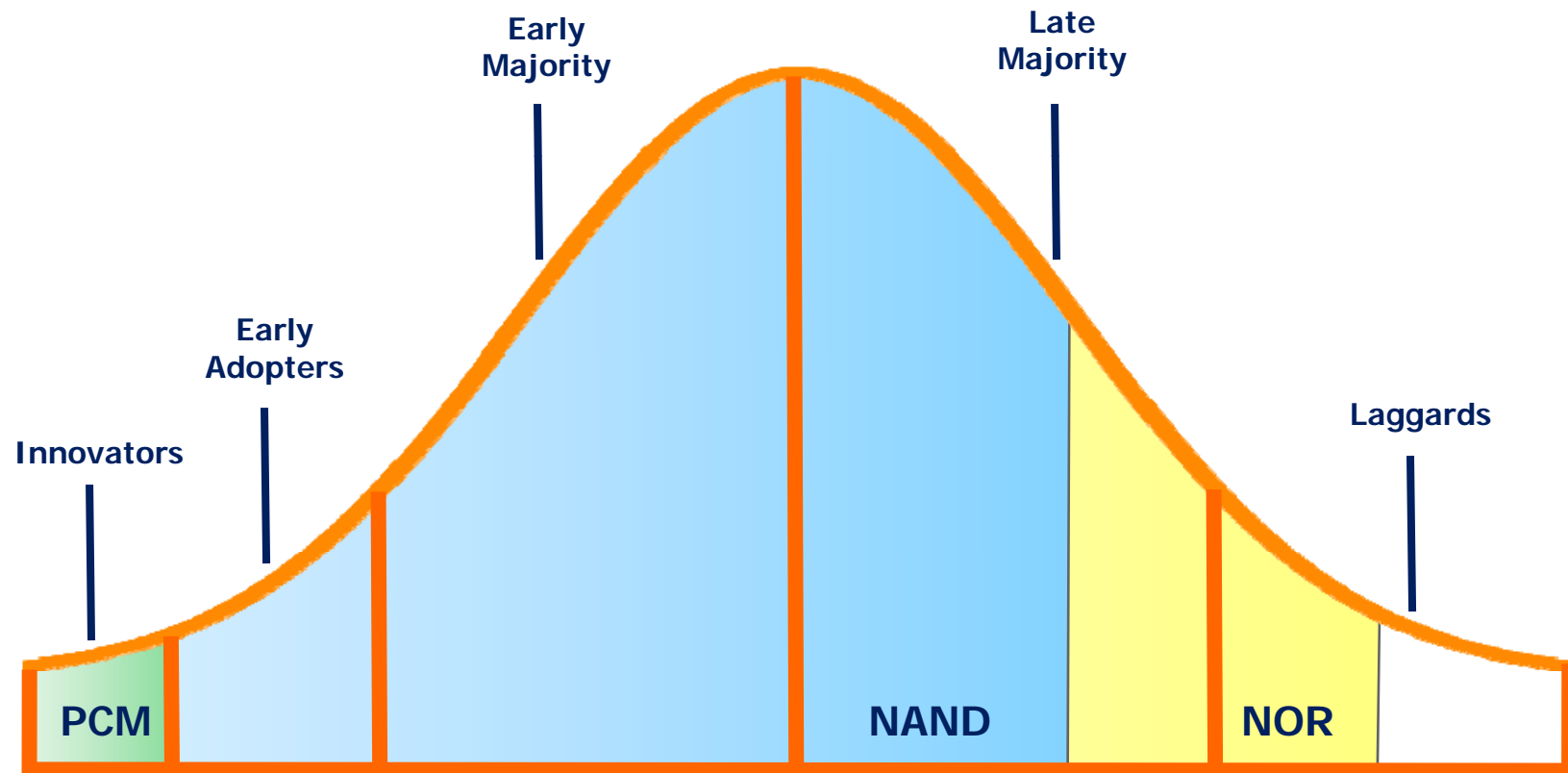
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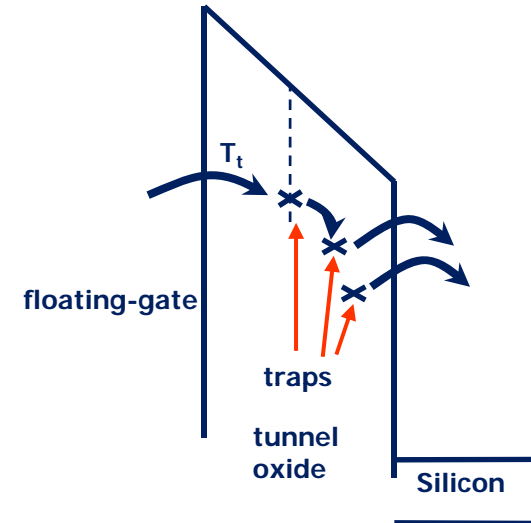
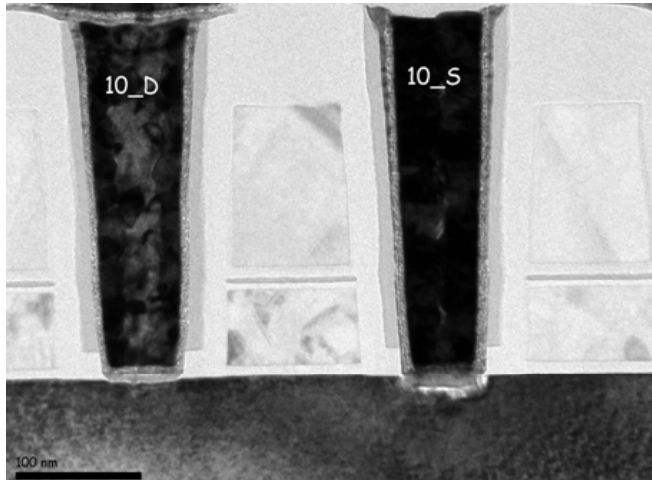
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Technology Lifecycle



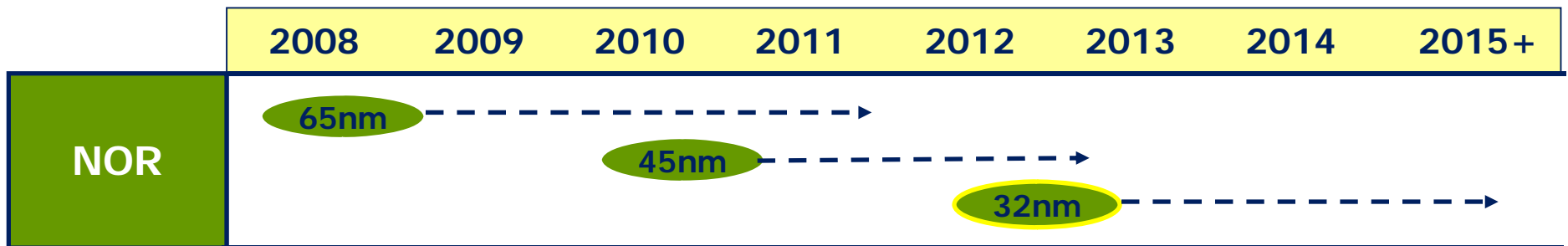
NOR Scaling



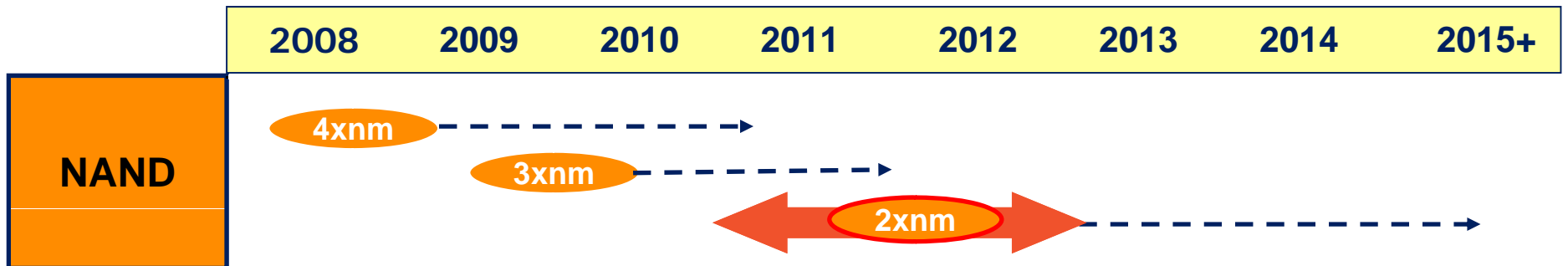
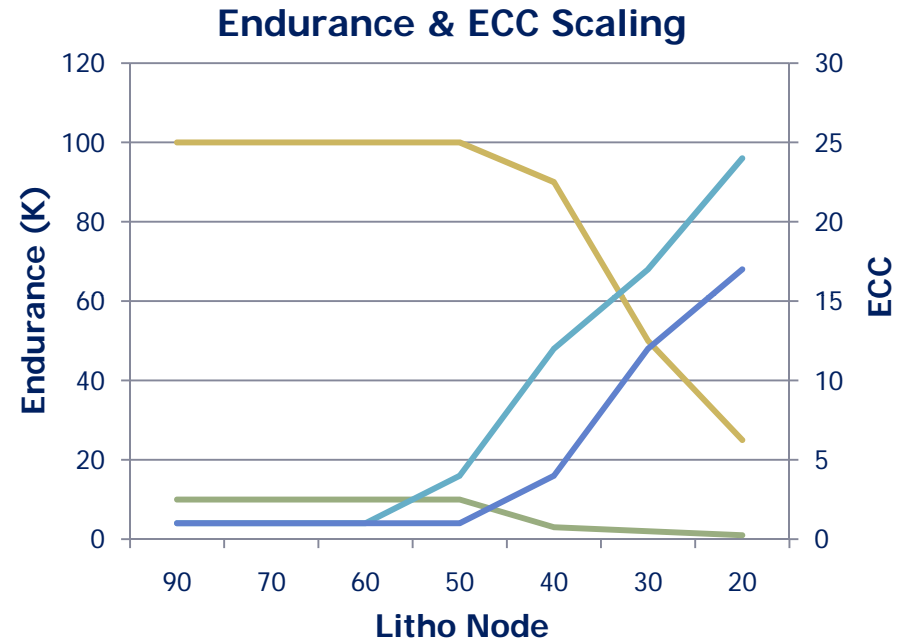
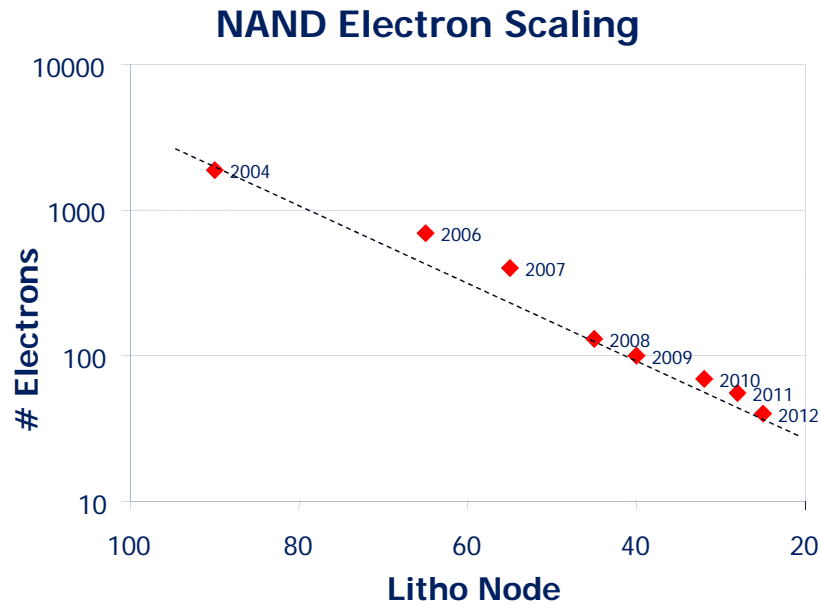
NOR (ETOX & NROM) Scaling:

3.2eV required to surmount Si-SiO₂ barrier → Limits Cell Gate Length Scaling

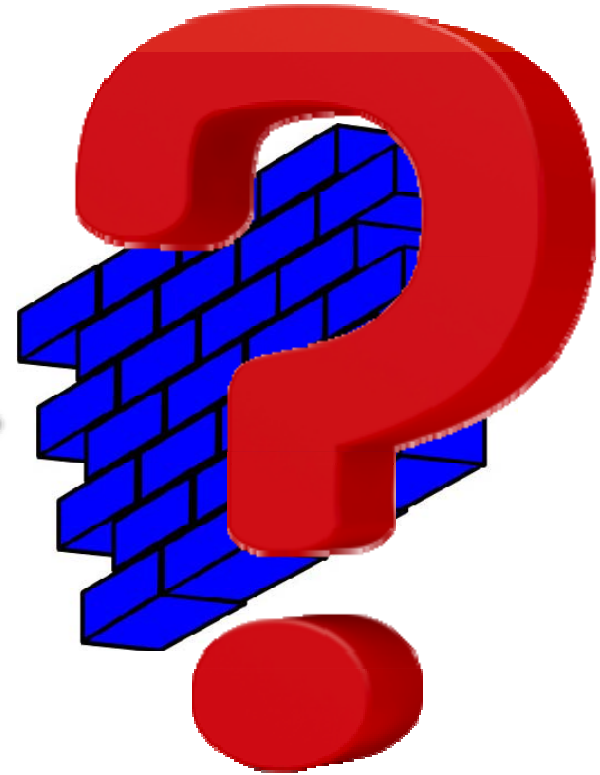
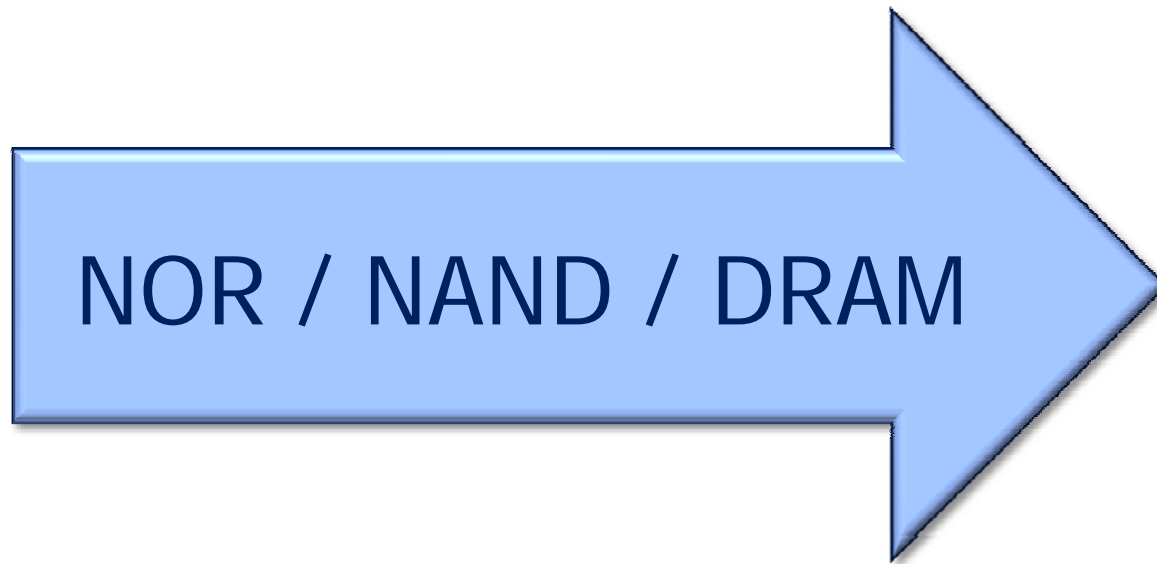
NOR Reliability: Write / Erase Tox traps leading to TAT or de-trapping of trapped oxide electrons



NAND Scaling



The 10's

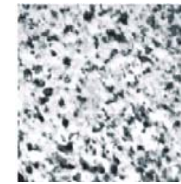


- The technology "Brick Wall"
- What can /should we do about it?
- What's beyond the brick wall?

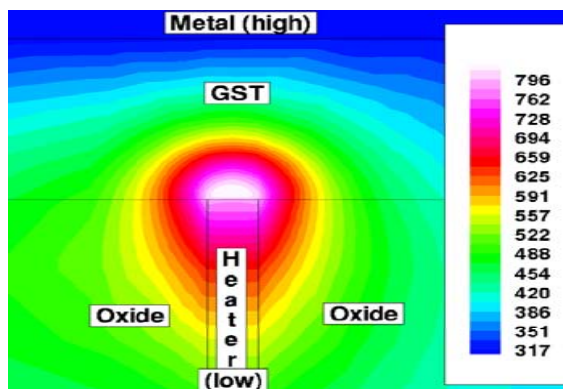
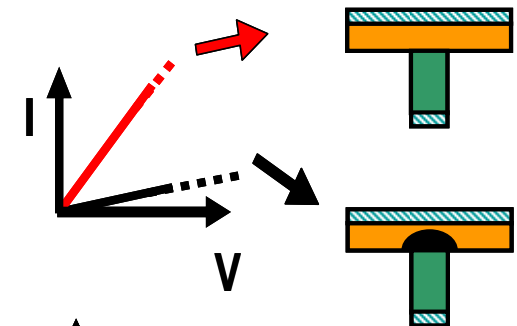
Phase Change Memory

- Storage
 - ▶ GST: Germanium-Antimony-Tellurium Chalcogenide glass
 - ▶ Cell states varying from amorphous (high resistance) to crystalline (low resistance) states
- Read Operation
 - ▶ Measure resistance of the GST
- Write Operation
 - ▶ Heat GST via current flow (Joule effect)
 - ▶ Time at critical temperature determines cell state

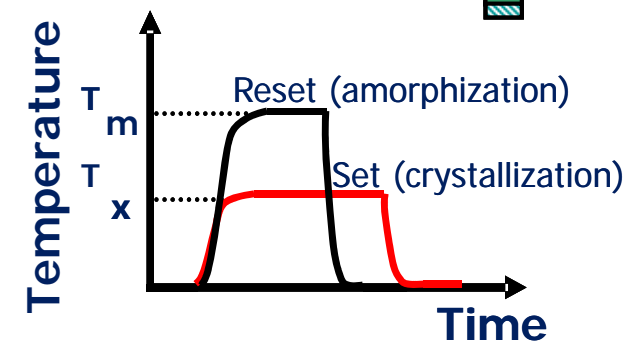
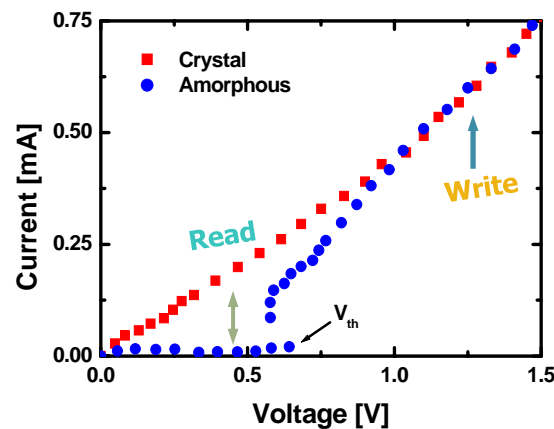
Crystalline



Amorphous

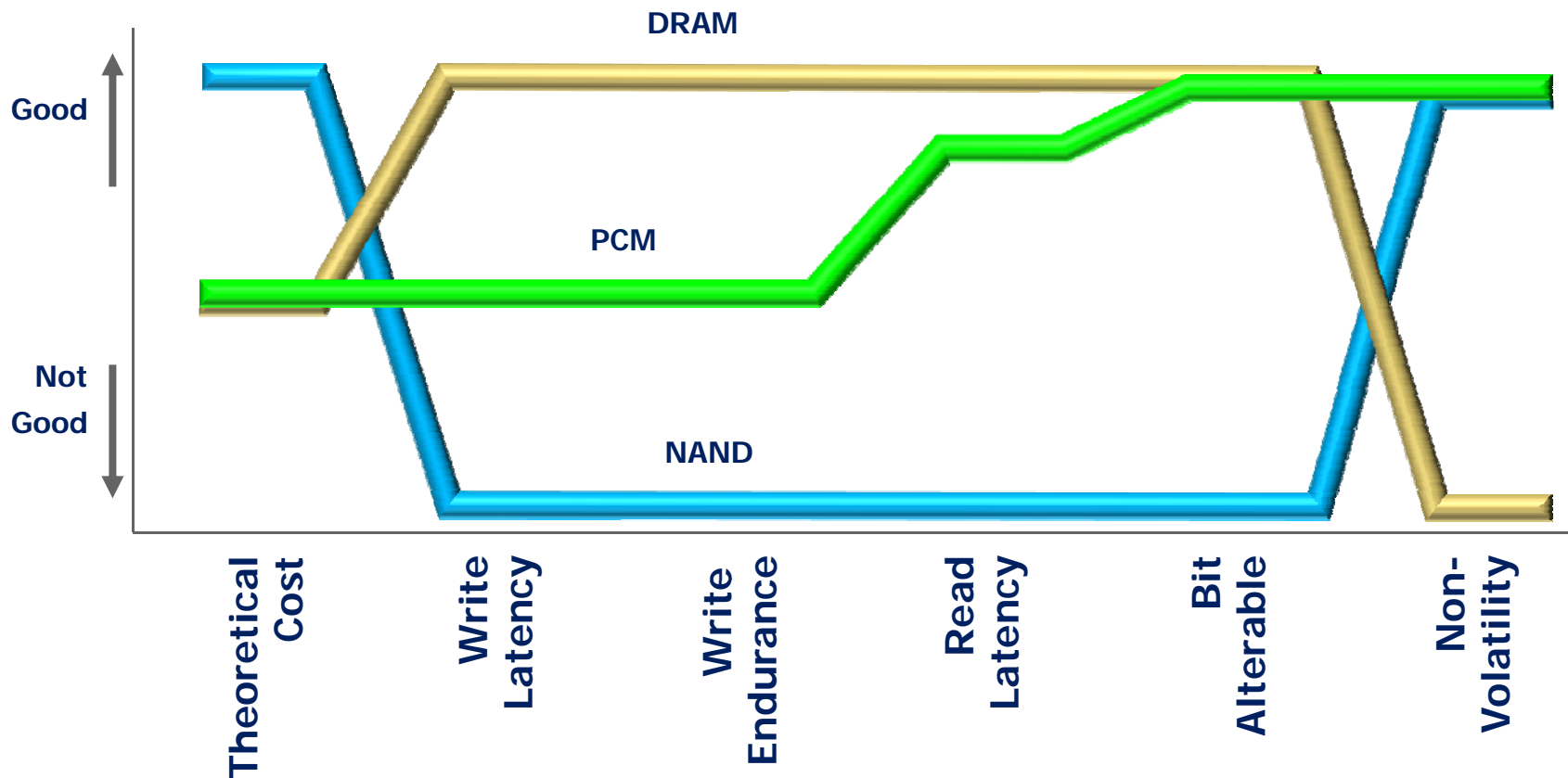


Temperature during write



Memory Characteristics

PCM Offers Attributes of RAM & NAND



Performance & Density Comparisons

Circa 2011, 45nm Silicon

Attributes	DRAM	PCM	NAND	HDD
Non-Volatile	No	Yes	Yes	Yes
Idle Power	~100mW/GB	~1 mW/GB	~1 mW/GB	~10W
Erase / Page Size	No / 64Byte	No / 32Byte	Yes / 256KB	No / 512Byte
Write Bandwidth	~GB/s per die	50-100 MB/s per die	5-40 MB/s per die	~200MB/s per drive
Page Write Latency	20-50 ns	~1 us	~500 us	~5 ms
Page Read Latency	20-50 ns	~70 ns	~25 μ s	~5 ms
Endurance	∞	$10^6 \rightarrow 10^7$	$10^5 \rightarrow 10^4$	∞
Maximum Density	4Gbit	4Gbit	64Gbit	2TByte

Theoretical Cost

Theoretical Chip Cost Factors

Silicon Cost Component		SLC PCM	DRAM	SLC NAND
Die Size	Cell Size (F ²)	5.5	6.0	5.0
	4G Prod Example	1.0x	1.2x	1.0x
Wafer Complexity	Total Process Mask Count	~35	~34	30
	300mm cost structure	1.2x	1.2x	1.0x
Theoretical Die Cost Summary		1.2x	1.4x	1.0x

- PCM will be cheaper than DRAM at lithography parity
- PCM scales to lower densities better than NAND
- PCM attributes can also save cost at system level

Bit Alterability

Bit Alterability

Ridiculously Simple

I have a new
mobile number:
(555) 555-5554



NAND

1. Read 4KB from NAND w/ECC
2. Write to RAM
3. Modify RAM
4. Locate new NAND page
5. Write new NAND page
6. Calculate & Write ECC
7. Mark old NAND page "dirty"
8. Eventually erase NAND block

PCM

1. Write 1 bit in PCM

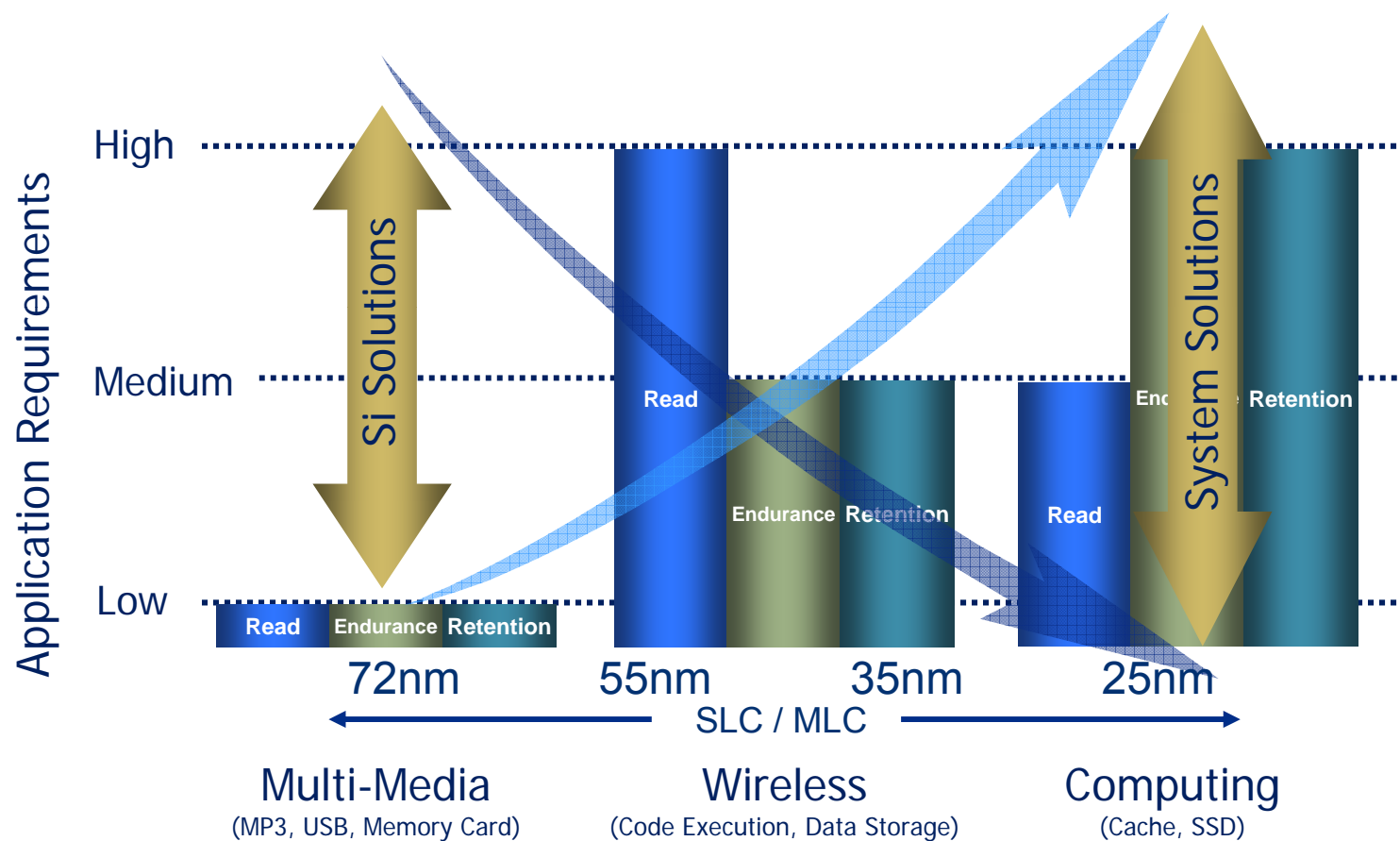
Much less bus traffic

"Hidden" Power

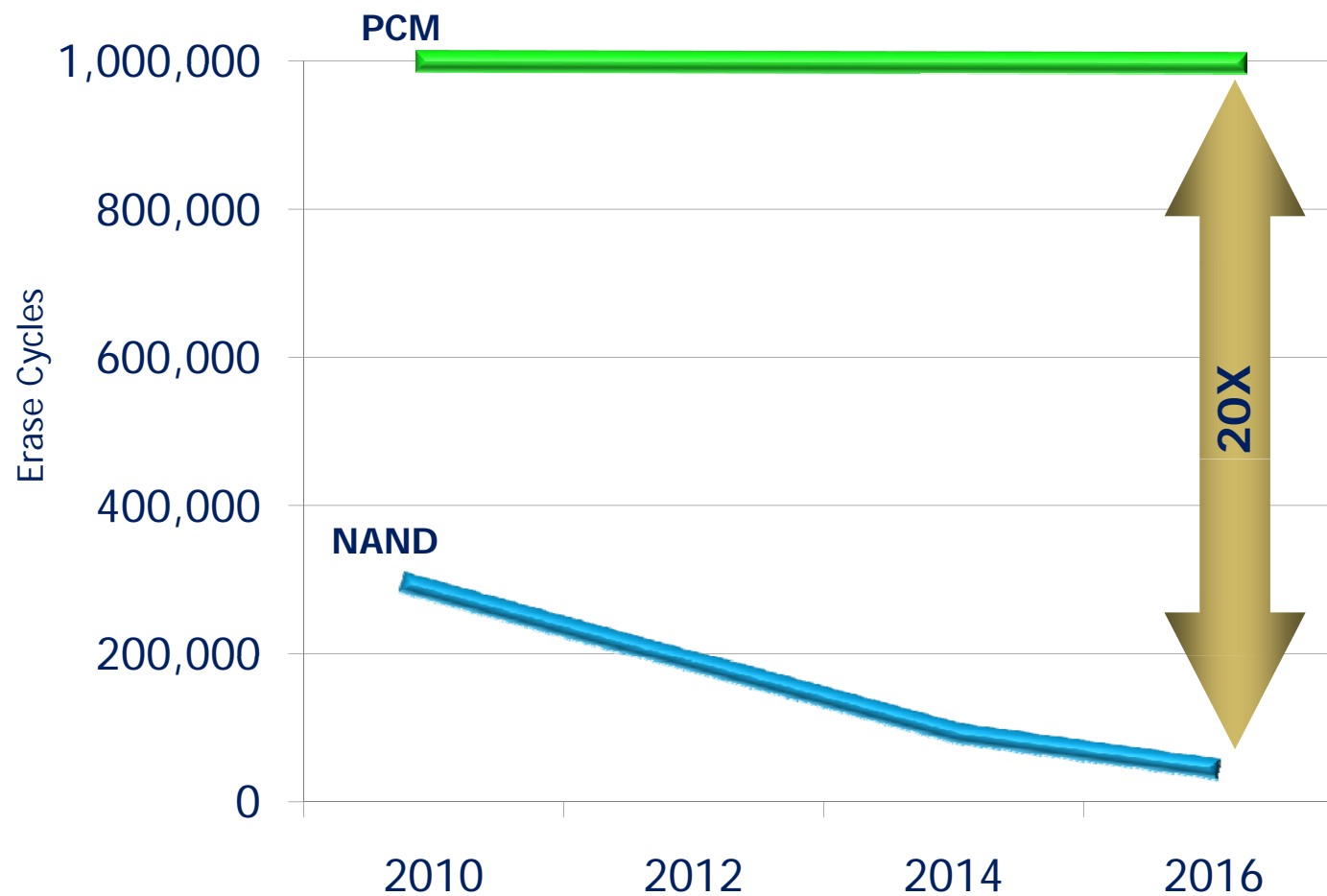
Ridiculously Simple

Endurance & Retention

Reliability System Implications

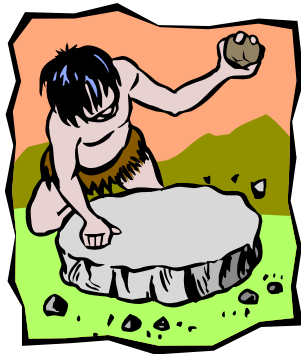


Endurance Scalability

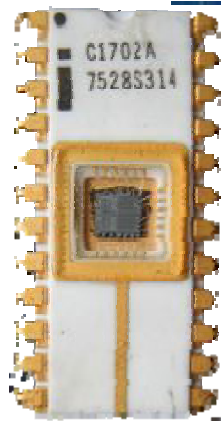


Source: My Estimates

Data Retention Historical View



200k year?



IEEE Standard Definitions and Characterization of Floating Gate Semiconductor Arrays

Sponsor
Standards Committee
of the
IEEE Electron Devices Society

Approved 25 June 1998
IEEE-SA Standards Board

IEEE 1005-1998
(Revision of IEEE Std 1005-1991)

JEDEC STANDARD

**Electrically Erasable Programmable
ROM (EEPROM) Program/Erase
Endurance and Data Retention Stress
Test**

JESD22-A117A
(revision of JESD22-A117, January 2000)

MARCH 2006

JEDEC Solid State Technology Association

JEDEC

EIA
Electronic Industries Alliance

"Endurance is a measure of the ability of a nonvolatile memory device to meet its data sheet specifications as a function of accumulated nonvolatile data rewrites or program/erase cycles."

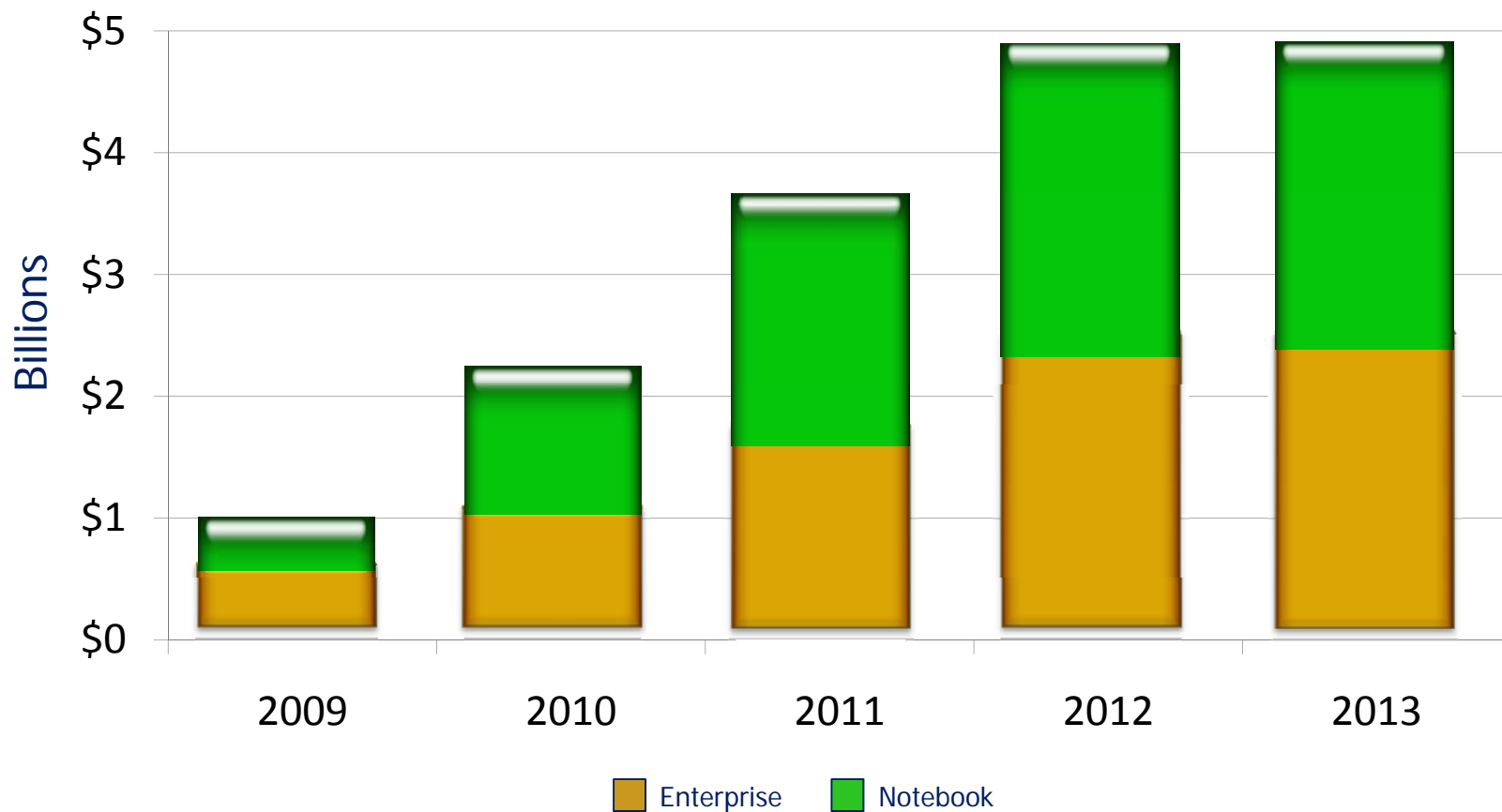
10 yr at "low cycles"
1 yr at data sheet



News Flash: PCM Retention is NOT a function of endurance

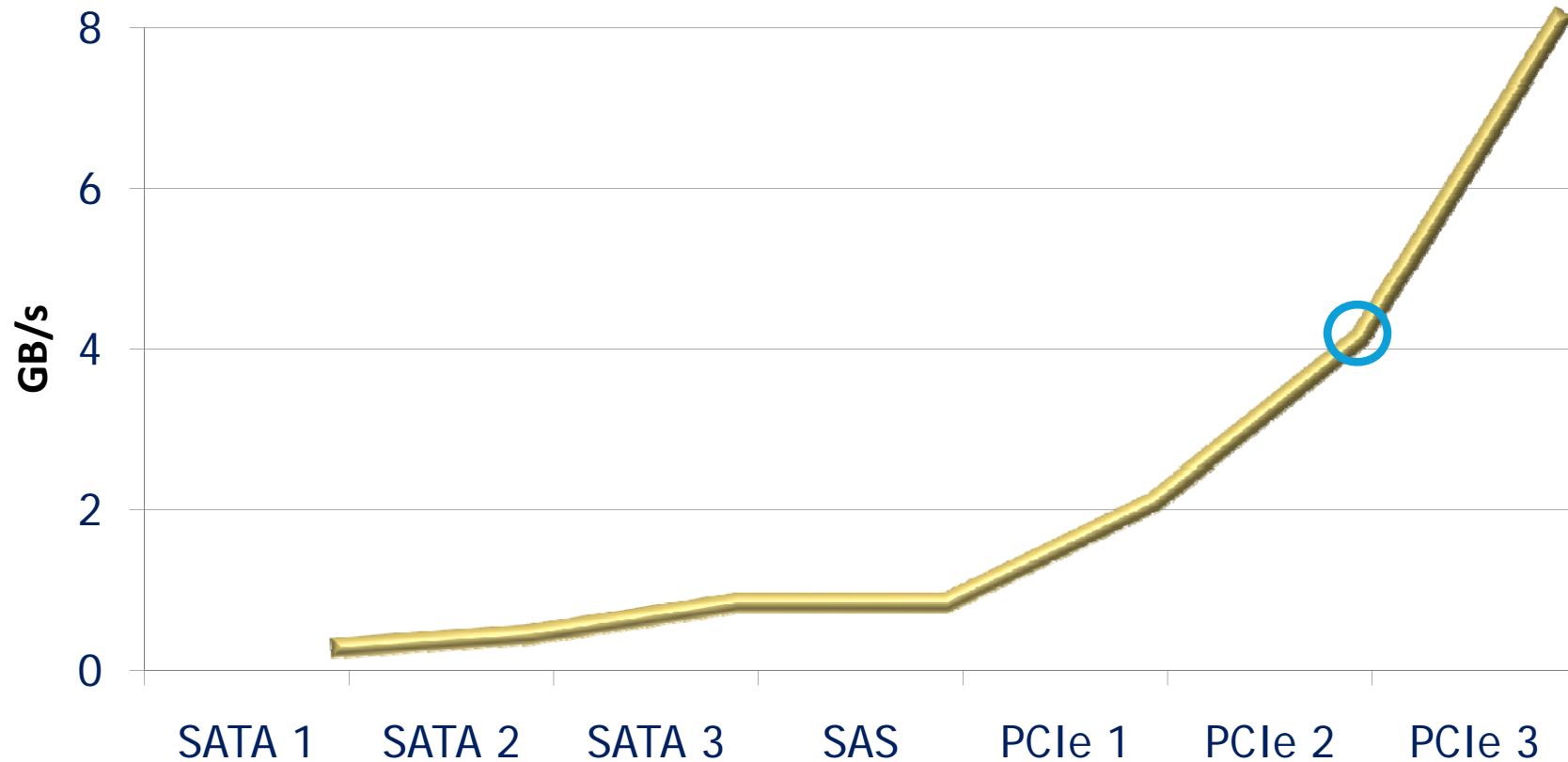
Endurance

SSD: Fast Growing Segment



Source: iSupply, Dec 2009

Interfaces Getting Faster



4GB/s at 90/10 Read/Write Equates to 34TB's per day

Note: PCIe x8

System Solutions

Endurance vs. Density

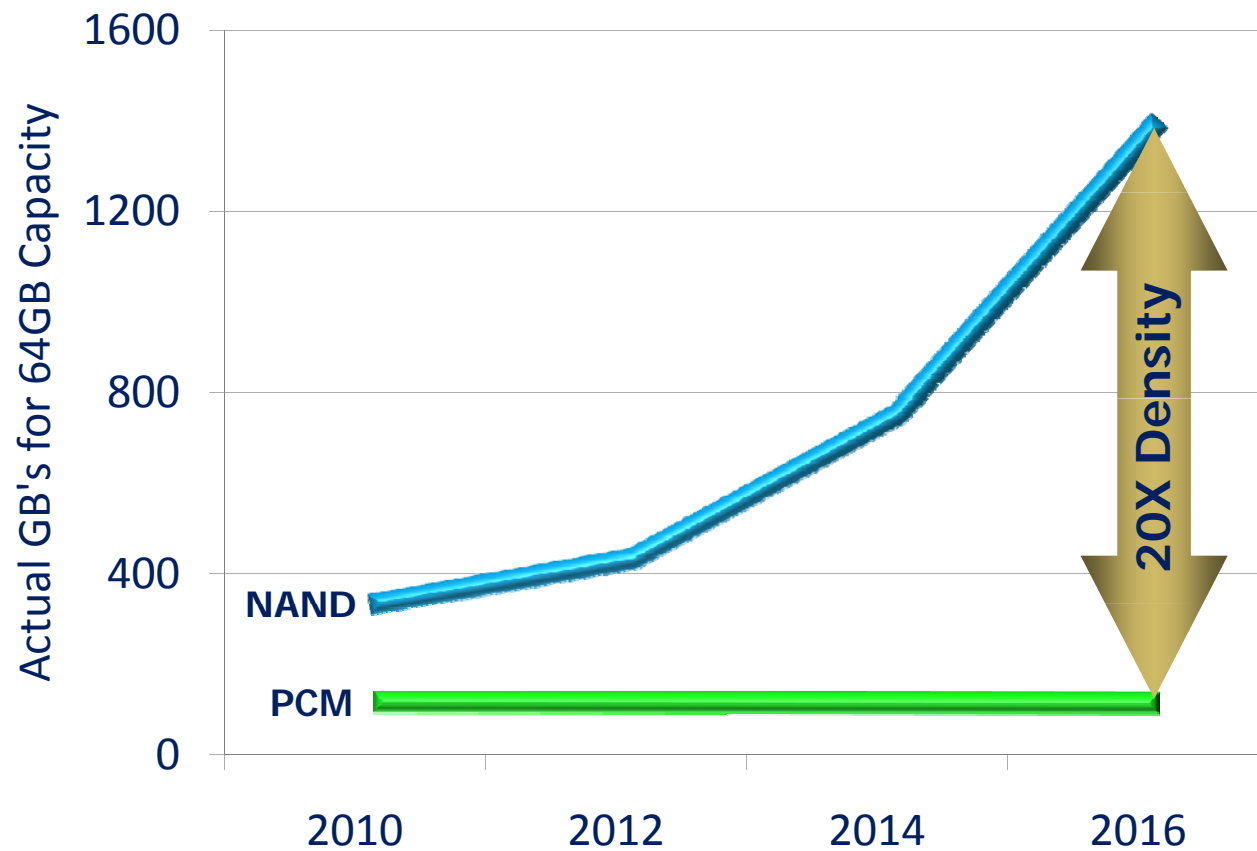
PCIe2



90/10



5 yrs



Latency

Performance

Bandwidth vs. Latency



Bandwidth
"Add More"



0-60mph → 10.4s
\$20,000

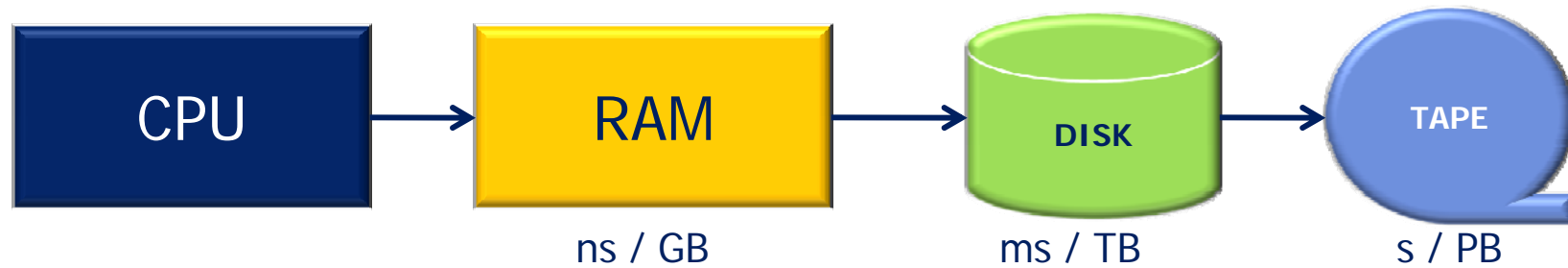


Latency
"Add Something Faster"



0-60mph → 3.5s
\$200,000

Application to Compute Approach is Changing



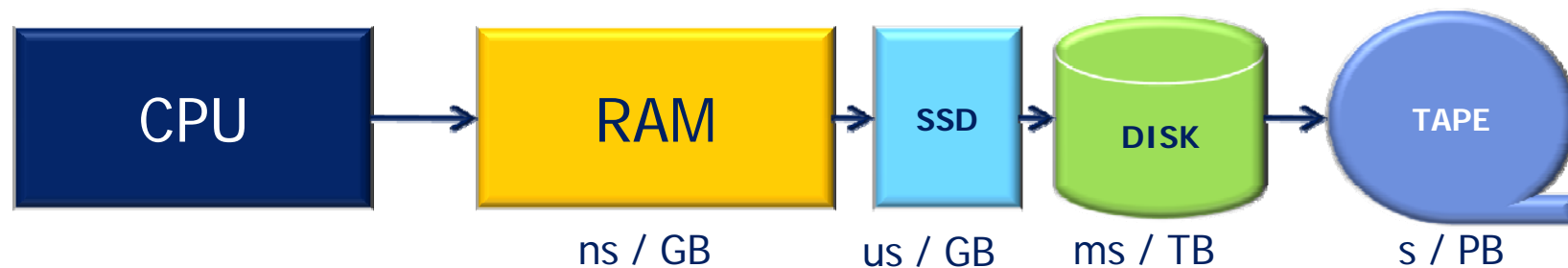
Bandwidth Improvement ➡



Latency Improvement ➡



or



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Performance Relatively Speaking

PCM

If Random Latency = **1 day**

SSD

Then... latency = **17 days**

HDD

Then... latency = **9 years**

SCM PCM

Then... latency = **30 min**

Storage Class PCM can perform >800 data
base searches in the time it takes an SSD to do 1

Latency

Value goes up with information growth



“... every 100ms of latency cost them 1% in sales”

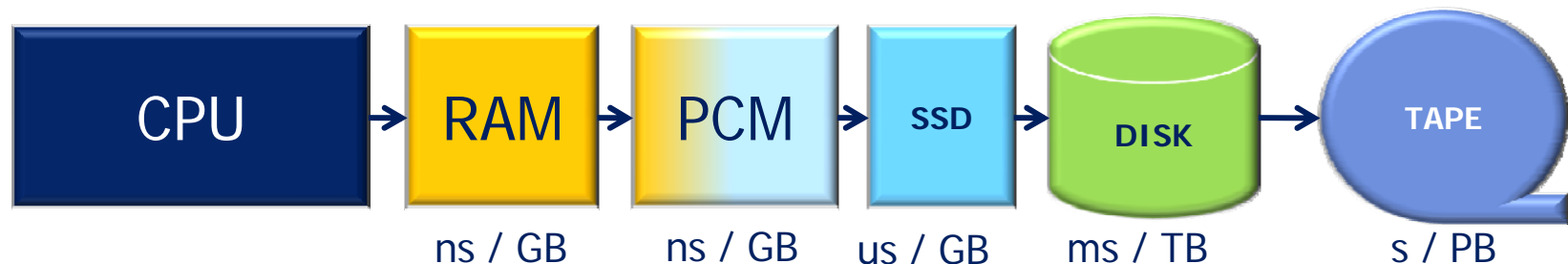


“...an extra 500ms in search page generation time dropped traffic by 20%”



“... a broker could lose \$4 Million Dollars per millisecond if their electronic trading platform is 5ms behind the competition”

Source: <http://highscalability.com>



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Latency

Still Not Convinced?

High Frequency Trader: Trading In Mere "Milliseconds" Is Like, So Last Century

Courtney Comstock | Mar. 4, 2010, 10:07 AM | 🔥 852 | 💬 5

🖨️ Print

Tags: Wall Street, High Frequency Trading

When we made the mistake of saying "milliseconds," instead of "microseconds" at a Mankoff Group HFT conference the other night, we were quickly corrected.

"Trading in milliseconds is from like, last century," a trader told us.

"The new frontier is microseconds," another added.

"We're trying to get to a speed where we can trade in 5 microseconds - actually it might even be down to 3 now."



PCM

Industry Demands Will Drive Change



